

B1500A Semiconductor Device Analyzer



Introduction

Keysight B1500A Semiconductor Device Analyzer of Precision Current-Voltage Analyzer Series is an all in one analyzer supporting IV, CV, pulse/dynamic IV and more, which is designed for all-round characterization from basic to cutting-edge applications. It provides a wide range of measurement capabilities to cover the electrical characterization and evaluation of devices, materials, semiconductors, active/passive components, or virtually any other type of electronic device with uncompromised measurement reliability and efficiency. In addition, the B1500A's modular architecture with ten available slots allows you to add or upgrade measurement modules if your measurement needs change over time.

Keysight EasyEXPERT group+ GUI based characterization software is available either on the B1500A's embedded Windows 10 platform with 15-inch touch screen or on your PC to accelerate the characterization tasks. It supports efficient and repeatable device characterization in the entire characterization process from measurement setup and execution to analysis and data management either interactive manual operation or automation across a wafer in conjunction with a semiautomatic wafer prober. EasyEXPERT group+ makes it easy to perform complex device characterization immediately with hundreds of ready-to-use measurements (application tests) furnished, and allows you the option of storing test condition and measurement data automatically after each measurement in a unique built-in database (workspace), ensuring that valuable information is not lost and that measurements can be repeated at a later date. Keysight B1500A provides the complete solution for device characterization with these versatile capabilities.

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Basic Features

Measurement capabilities

Current versus voltage (IV) measurement

- Accurate and precise measurement ranges of 0.1 fA - 1 A and 0.5 μ V - 200 V
- Spot and sweep measurement
- Time sampling measurements (100 μ s minimum sampling rate)
- Pulsed measurement with minimum pulse widths of 50 μ s using the MCSMU or 500 μ s using the HPSMU, MPSMU, or HRSMU
- The ASU (atto-sense and switch unit) can be used with the MPSMU, or HRSMU to provide 0.1 fA measurement resolution and SMU/AUX path switching
- Two analog-to-digital converter choices (high-resolution ADC or high-speed ADC) available for each SMU type (HPSMU, MPSMU and HRSMU)

Capacitance measurement

- Multi-frequency AC impedance measurement supports CV (capacitance versus voltage), C-t (capacitance versus time) and C-f (capacitance versus frequency) measurement
- Capacitance measurement frequency range of 1 kHz to 5 MHz
- Quasi-Static Capacitance-Voltage (QS-CV) measurement with leakage current compensation
- Automated switching between IV and CV measurements using either the optional SCUU (SMU CMU unify unit) and GSWU (guard switch unit) or a pair of ASUs

Pulsed IV/Fast IV/Transient IV measurement

- Provides high speed and high sensitivity measurement capability for ultra-fast IV (current-voltage), pulsed IV and transient IV measurements, including NBTI/PBTI and RTN (Random Telegraph Signal Noise) measurements
- Arbitrary waveform generation with 10 ns programmable resolution
- Simultaneous high-speed voltage/current measurement (200 MSa/s, 5 ns sampling rate)
- SMU technology supports pulsed IV measurement without load line effects

Pulse Generation

- Up to ± 40 V voltage pulsing and arbitrary waveform generation for non-volatile memory evaluation
- Single channel two-level and three level pulsing capability

B1500A platform:

- 15-inch touch screen supports all capabilities of the intuitive GUI for convenient device characterization
- Configurable and upgradable measurement modules with 10 slots per mainframe
- GPIB, USB, LAN interfaces, and VGA video output port

EasyEXPERT group+ software:

- Characterization environment is available either on mainframe (embedded Windows 10) or on user's PC
- Intuitive GUI based operation with keyboard, mouse operation and touch screen.
- Application Test mode provides the furnished hundreds of ready-to-use application tests for quick measurement execution
- Classic test mode provides easy access to the full capability of instrument features.
- Graphical display and analysis capabilities facilitate front-end data analysis without additional utilities and support report generation as image data or Excel data.
- Individualized built-in database (workspace) records test data automatically, and simplifies the data management without annoying numerous data files.
- Tracer test mode enables a curve tracer like knob control of measurement parameters to support interactive real-time device characterization and automatic data recording feature
- Oscilloscope view (available for the MCSMU) supports pulsed voltage and current waveform viewing for quick and easy timing verification
- Quick test mode supports test sequencing without programming
- GUI-based control of the Keysight B2200A, B2201A and E5250A switching matrices
- GUI-based self-test, self-calibration and diagnostics menu for hardware maintenance
- EasyEXPERT remote control function supports the remote measurement execution of application tests that are created on GUI interactively, via the LAN interface
- Data back capability and various data protection feature for shared usage by multiple users
- EasyEXPERT group+ can be installed on as many PCs as you need without additional charge to take advantage of offline personal analyzer environment among users in your department.

Specification conditions

The measurement and output accuracy are specified at the rear panel connector terminals when referenced to the Zero Check terminal. The B1530A WGFMU measurement and output accuracy are specified at the output terminal of the RSU. Accuracy is specified under the following conditions:

1. Temperature: 23°C $\pm$ 5°C
2. Humidity: 20% to 60%
3. After 40 minutes warm-up followed by self-calibration
4. Ambient temperature changes less than $\pm$ 1°C after self-calibration execution, not applicable for MFCMU and WGFMU
5. Measurement made within one hour after self-calibration execution, not applicable for MFCMU and WGFMU
6. Calibration period: 1 year

7. SMU integration time setting:
 - 1 PLC (1 nA to 1A range, voltage range)
 - 20 PLC (100 pA range)
 - 50 PLC (1 pA to 10 pA range)
 - Averaging of high-speed ADC: 128 samples per 1 PLC
8. SMU filter: ON (for HPSMU, MPSMU and HRSMU)
9. SMU measurement terminal connection: Kelvin connection
10. WGF MU load capacitance: 25 pF or less

Note: This document lists specifications and supplemental characteristics for the B1500A and its associated modules. The specifications are the standards against which the B1500A and its associated modules are tested. When the B1500A and any of its associated modules are shipped from the factory, they meet the specifications. The “supplemental” characteristics described in the following specifications are not warranted, but provide useful information about the functions and performance of the instrument.

Note: Keysight is responsible for removing, installing, and replacing the B1500A modules. Contact your nearest Keysight to install and calibrate the B1500A modules.

B1500A Mainframe Specifications

Supported plug-in modules

The B1500A supports ten slots for plug-in modules.

Module Name	Slots occupied	Key Features
B1510A High power source/monitor unit (HPSMU)	2	- Range up to 200 V/1 A with 4-quadrant operation - Minimum measurement resolution 10 fA/2 μV
B1511B Medium power source/monitor unit (MPSMU)	1	- Range up to 100 V/0.1 A with 4-quadrant operation - Minimum measurement resolution 10 fA/0.5 μV - Optional ASU (atto-sense and switch unit) for 100 aA resolution and IV/CV switching capability
B1517A High resolution source/monitor unit (HRSMU)	1	- Range up to 100 V/0.1 A with 4-quadrant operation - Minimum measurement resolution 1 fA/0.5 μV - Optional ASU (atto-sense and switch unit) for 100 aA resolution and IV/CV switching capability
B1514A 50 μ s Pulse medium current source/monitor unit (50 μ s Pulse MCSMU)	1	- Range up to 30 V/1 A pulsed (0.1 A DC) with 4-quadrant operation - Pulse measurement from 50 μs pulse width with 2 μs resolution - Oscilloscope view (voltage/current waveform viewer) is supported - Minimum measurement resolution 10 pA/0.2 μV
B1520A Multi-frequency capacitance measurement unit (MFCMU)	1	- AC impedance measurement (C-V, C-f, C-t) 1 kHz to 5 MHz frequency range with minimum 1 MHz frequency resolution 25 V built-in DC bias and 100 V DC bias with SMU and SCUU (SMU CMU Unify Unit) - Easy and fast yet accurate IV and CV automated connection change by SCUU

B1525A High voltage semiconductor pulse generator unit (HV-SPGU)	1	- High voltage output up to ± 40 V applicable for non-volatile memory testing - Two-level and three-level pulse capability by single channel - Flexible arbitrary waveform generation with 10 ns resolution (arbitrary linear waveform generation function) - Two channels per module
B1530A Waveform generator/fast measurement unit (WGFMU)	1	- Ultra-fast IV measurement capability for the pulsed IV and transient IV such as NBTI/PBTI, RTN, etc. - Waveform generation with 10 ns programmable resolution - Simultaneous high-speed IV measurement capability (200 MSa/s, 5 ns sampling rate) 10 V peak-to-peak output - No load line effect accurate pulsed IV measurement by dynamic SMU technology

Maximum module configuration

The total power consumption of all SMU modules cannot exceed 84 W. Under this rule, the B1500A can contain any combination of the following SMUs:

- Up to 10 MPSMUs
- Up to 10 HRSMUs
- Up to 4 HPSMUs
- Up to 4 MCSMUs

Only one single-slot MFCMU can be installed per B1500A mainframe. Up to five single-slot HV-SPGUs can be installed per mainframe. Up to five single-slot WGFMUs can be installed per mainframe.

When one or more WGFMU modules are installed in the B1500A mainframe, the following table applies. Multiply the values given below by the number of installed modules of that type and add the products together. The sum of the products must be less than or equal to 59 for the configuration to be permissible.

MPSMU	2
HRSMU	2
HPSMU	14
MCSMU	5
MFCMU	7
HV-SPGU	12
WGFMU	10

Maximum voltage between common and ground

$\leq \pm 42$ V

Ground unit (GNDU) specification

The GNDU is furnished standard with the B1500A mainframe.

Output voltage: 0 V $\pm$ 100 μ V

Maximum sink current: $\pm$ 4.2 A

Output terminal/connection: Triaxial connector, Kelvin (remote sensing)

GNDU supplemental characteristics

Load capacitance: 1 μ F

Cable resistance:

- For $I_S \leq 1.6$ A: force line $R < 1 \Omega$
- For $1.6 \text{ A} < I_S \leq 2.0$ A: force line $R < 0.7 \Omega$
- For $2.0 \text{ A} < I_S \leq 4.2$ A: force line $R < 0.35 \Omega$
- For all cases: sense line $R \leq 10 \Omega$
- Where I_S is the current being sunk by the GNDU.

Peripherals and interface

Data storage

SSD, DVD-R drive

Interfaces

GPIB, interlock, USB (USB 2.0, front 2, rear 2), LAN (1000BASE-T/100BASE-TX/10BASE-T), trigger in/out, digital I/O, VGA video output

Remote control capabilities

- FLEX commands (GPIB)
- EasyEXPERT remote control function (LAN)

Trigger I/O

- Only available using GPIB FLEX commands.
- Trigger in/out synchronization pulses before and after setting and measuring DC voltage and current. Arbitrary trigger events can be masked or activated independently.

Furnished accessories

- Keyboard
- Mouse
- Stylus pen
- Power cable
- Software entitlement document for EasyEXPERT

Furnished software

- EasyEXPERT group+
- MDM file converter

This tool can convert the EasyEXPERT file (XTR/ZTR) to Keysight IC-CAP MDM file format.

The EasyEXPERT file of the following measurements performed in the classic mode is only supported:

- IV Sweep
 - Multi channel IV Sweep
 - CV Sweep
- 4155/56 setup file converter tool

This tool can convert 4155 and 4156 measurement setup files (file extensions MES or DAT) into equivalent EasyEXPERT classic test mode setup files.

MPSMU and HRSMU Module Specifications

Voltage range, resolution, and accuracy (high resolution ADC)

Voltage range	Force resolution	Measure resolution	Force accuracy ¹	Measure accuracy ¹	Maximum current
±0.5 V	25 µV	0.5 µV	±(0.018% + 150 µV)	±(0.01% + 120 µV)	100 mA
±2 V	100 µV	2 µV	±(0.018% + 400 µV)	±(0.01% + 140 µV)	100 mA
±5 V	250 µV	5 µV	±(0.018% + 750 µV)	±(0.009% + 250 µV)	100 mA
±20 V	1 mV	20 µV	±(0.018% + 3 mV)	±(0.009% + 900 µV)	100 mA
±40 V	2 mV	40 µV	±(0.018% + 6 mV)	±(0.01% + 1 mV)	²
±100 V	5 mV	100 µV	±(0.018% + 15 mV)	±(0.012% + 2.5 mV)	²

1. ± (% of read value + offset voltage V)

2. 100 mA ($V_o \leq 20$ V), 50 mA (20 V < $V_o \leq 40$ V), 20 mA (40 V < $V_o \leq 100$ V), V_o is the output voltage in Volts.

Current range, resolution, and accuracy (high resolution ADC)

SMU type		Current range	Force resolution	Measure resolution ^{1,2}	Force accuracy ³	Measure accuracy ³	Maximum voltage
MPSMU w/ ASU	HRSMU w/ ASU	±1 pA	1 fA	100 aA	±(0.9%+15 fA)	±(0.9%+12 fA)	100 V
	HRSMU	±10 pA	5 fA	400 aA (with ASU) 1 fA (HRSMU)	±(0.46%+30 fA+10 aA x Vo)	±(0.46%+15 fA+10 aA x Vo)	100 V
		±100 pA	5 fA	500 aA (with ASU) 2 fA (HRSMU)	±(0.3%+100 fA+100 aA x Vo)	±(0.3%+30 fA+100 aA x Vo)	100 V
MPSMU		±1 nA	50 fA	10 fA	±(0.1%+300 fA+1 fA x Vo)	±(0.1%+200 fA+1 fA x Vo)	100 V
		±10 nA	500 fA	10 fA	±(0.1%+3 pA+10 fA x Vo)	±(0.1%+1 pA+10 fA x Vo)	100 V
		±100 nA	5 pA	100 fA	±(0.05%+30 pA+100 fA x Vo)	±(0.05%+20 pA+100 fA x Vo)	100 V
		±1 µA	50 pA	1 pA	±(0.05%+300 pA+1 pA x Vo)	±(0.05%+100 pA+1 pA x Vo)	100 V
		±10 µA	500 pA	10 pA	±(0.05%+3 nA+10 pA x Vo)	±(0.04%+2 nA+10 pA x Vo)	100 V
		±100 µA	5 nA	100 pA	±(0.035%+15 nA+100 pA x Vo)	±(0.03%+3 nA+100 pA x Vo)	100 V
		±1 mA	50 nA	1 nA	±(0.04%+150 nA+1 nA x Vo)	±(0.03%+60 nA+1 nA x Vo)	100 V
		±10 mA	500 nA	10 nA	±(0.04%+1.5 µA+10 nA x Vo)	±(0.03%+200 nA+10 nA x Vo)	100 V
		±100 mA	5 µA	100 nA	±(0.045%+15 µA+100 nA x Vo)	±(0.04%+6 µA+100 nA x Vo)	100 V ⁴

1. Specified measurement resolution is limited by fundamental noise limits. Minimum displayed resolution is 1 aA at 1 pA range by 6 digits.
2. Measurements made in the lower ranges can be greatly impacted by vibrations and shocks. These specifications assume an environment free of these factors.
3. ± (% of read value + offset current (fixed part determined by the output/measurement range + proportional part that is multiplied by Vo))
4. 100 V (Io ≤ 20 mA), 40 V (20 mA < Io ≤ 50 mA), 20 V (50 mA < Io ≤ 100 mA), Io is the output current in Amps.

Voltage range, resolution, and accuracy (high speed ADC)

Voltage range	Force resolution	Measure resolution	Force accuracy ¹	Measure accuracy ¹	Maximum current
±0.5 V	25 µV	25 µV	±(0.018% + 150 µV)	±(0.01% + 250 µV)	100 mA
±2 V	100 µV	100 µV	±(0.018% + 400 µV)	±(0.01% + 700 µV)	100 mA
±5 V	250 µV	250 µV	±(0.018% + 750 µV)	±(0.01% + 2 mV)	100 mA
±20 V	1 mV	1 mV	±(0.018% + 3 mV)	±(0.01% + 4 mV)	100 mA

± 40 V	2 mV	2 mV	$\pm(0.018\% + 6 \text{ mV})$	$\pm(0.015\% + 8 \text{ mV})$	²
± 100 V	5 mV	5 mV	$\pm(0.018\% + 15 \text{ mV})$	$\pm(0.02\% + 20 \text{ mV})$	²

1. $\pm$ (% of read value + offset voltage V)

2. 100 mA ($V_o \leq 20$ V), 50 mA ($20 \text{ V} < V_o \leq 40$ V), 20 mA ($40 \text{ V} < V_o \leq 100$ V), V_o is the output voltage in Volts.

Current range, resolution, and accuracy (high speed ADC)

SMU type		Current range	Force resolution	Measure resolution ^{1,2}	Force accuracy ³	Measure accuracy ³	Maximum voltage
MPSMU w/ ASU	HRSMU w/ ASU	± 1 pA	1 fA	100 aA	$\pm(0.9\%+15 \text{ fA})$	$\pm(1.8\%+12 \text{ fA})$	100 V
	HRSMU	± 10 pA	5 fA	1 fA	$\pm(0.46\%+30 \text{ fA}+10 \text{ aA} \times V_o)$	$\pm(0.5\%+15 \text{ fA}+10 \text{ aA} \times V_o)$	100 V
		± 100 pA	5 fA	5 fA	$\pm(0.3\%+100 \text{ fA}+100 \text{ aA} \times V_o)$	$\pm(0.5\%+40 \text{ fA}+100 \text{ aA} \times V_o)$	100 V
MPSMU		± 1 nA	50 fA	50 fA	$\pm(0.1\%+300 \text{ fA}+1 \text{ fA} \times V_o)$	$\pm(0.25\%+300 \text{ fA}+1 \text{ fA} \times V_o)$	100 V
		± 10 nA	500 fA	500 fA	$\pm(0.1\%+3 \text{ pA}+10 \text{ fA} \times V_o)$	$\pm(0.25\%+2 \text{ pA}+10 \text{ fA} \times V_o)$	100 V
		± 100 nA	5 pA	5 pA	$\pm(0.05\%+30 \text{ pA}+100 \text{ fA} \times V_o)$	$\pm(0.1\%+20 \text{ pA}+100 \text{ fA} \times V_o)$	100 V
		± 1 μ A	50 pA	50 pA	$\pm(0.05\%+300 \text{ pA}+1 \text{ pA} \times V_o)$	$\pm(0.1\%+200 \text{ pA}+1 \text{ pA} \times V_o)$	100 V
		± 10 μ A	500 pA	500 pA	$\pm(0.05\%+3 \text{ nA}+10 \text{ pA} \times V_o)$	$\pm(0.05\%+2 \text{ nA}+10 \text{ pA} \times V_o)$	100 V
		± 100 μ A	5 nA	5 nA	$\pm(0.035\%+15 \text{ nA}+100 \text{ pA} \times V_o)$	$\pm(0.05\%+20 \text{ nA}+100 \text{ pA} \times V_o)$	100 V
		± 1 mA	50 nA	50 nA	$\pm(0.04\%+150 \text{ nA}+1 \text{ nA} \times V_o)$	$\pm(0.04\%+200 \text{ nA}+1 \text{ nA} \times V_o)$	100 V
		± 10 mA	500 nA	500 nA	$\pm(0.04\%+1.5 \text{ } \mu\text{A}+10 \text{ nA} \times V_o)$	$\pm(0.04\%+2 \text{ } \mu\text{A}+10 \text{ nA} \times V_o)$	100 V
		± 100 mA	5 μ A	5 μ A	$\pm(0.045\%+15 \text{ } \mu\text{A}+100 \text{ nA} \times V_o)$	$\pm(0.1\%+20 \text{ } \mu\text{A}+100 \text{ nA} \times V_o)$	⁴

1. Specified measurement resolution is limited by fundamental noise limits. Minimum displayed resolution is 1 aA at 1 pA range by 6 digits.

2. Measurements made in the lower ranges can be greatly impacted by vibrations and shocks. These specifications assume an environment free of these factors.

3. $\pm$ (% of read value + offset current (fixed part determined by the output/measurement range + proportional part that is multiplied by V_o))

4. 100 V ($I_o \leq 20$ mA), 40 V ($20 \text{ mA} < I_o \leq 50$ mA), 20 V ($50 \text{ mA} < I_o \leq 100$ mA), I_o is the output current in Amps.

Power consumption

Voltage source mode

Voltage range	Power
0.5 V	$20 \times I_c$ (W)
2 V	$20 \times I_c$ (W)
5 V	$20 \times I_c$ (W)
20 V	$20 \times I_c$ (W)
40 V	$40 \times I_c$ (W)
100 V	$100 \times I_c$ (W)

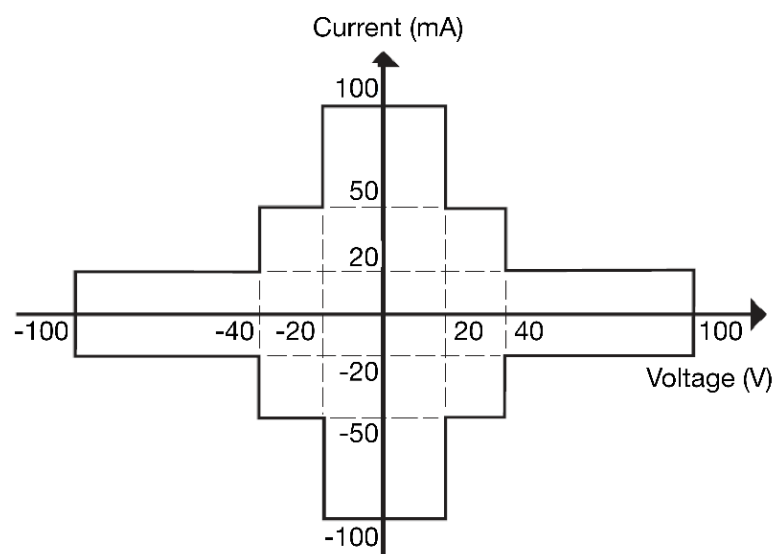
Where I_c is the current compliance setting.

Current source mode

Voltage compliance	Power
$V_c \leq 20$	$20 \times I_o$ (W)
$20 < V_c \leq 40$	$40 \times I_o$ (W)
$40 < V_c \leq 100$	$100 \times I_o$ (W)

Where V_c is the voltage compliance setting and I_o is output current

MPSMU and HRSMU measurement and output range



HPSMU Module Specifications

Voltage range, resolution, and accuracy (high resolution ADC)

Voltage range	Force resolution	Measure resolution	Force accuracy ¹	Measure accuracy ¹	Maximum current
±2 V	100 µV	2 µV	±(0.018% + 400 µV)	±(0.01% + 140 µV)	1 A
±20 V	1 mV	20 µV	±(0.018% + 3 mV)	±(0.009% + 900 µV)	1 A
±40 V	2 mV	40 µV	±(0.018% + 6 mV)	±(0.01% + 1 mV)	500 mA
±100 V	5 mV	100 µV	±(0.018% + 15 mV)	±(0.012% + 2.5 mV)	125 mA
±200 V	10 mV	200 µV	±(0.018% + 30 mV)	±(0.014% + 2.8 mV)	50 mA

1. ± (% of read value + offset voltage V)

Current range, resolution, and accuracy (high resolution ADC)

Current range	Force resolution	Measure resolution ¹	Force accuracy ²	Measure accuracy ²	Maximum voltage
±1 nA	50 fA	10 fA	±(0.1%+300 fA+1 fA x Vo)	±(0.1%+200 fA+1 fA x Vo)	200 V
±10 nA	500 fA	10 fA	±(0.1%+3 pA+10 fA x Vo)	±(0.1%+1 pA+10 fA x Vo)	200 V
±100 nA	5 pA	100 fA	±(0.05%+30 pA+100 fA x Vo)	±(0.05%+20 pA+100 fA x Vo)	200 V
±1 µA	50 pA	1 pA	±(0.05%+300 pA+1 pA x Vo)	±(0.05%+100 pA+1 pA x Vo)	200 V
±10 µA	500 pA	10 pA	±(0.05%+3 nA+10 pA x Vo)	±(0.04%+2 nA+10 pA x Vo)	200 V
±100 µA	5 nA	100 pA	±(0.035%+15 nA+100 pA x Vo)	±(0.03%+3 nA+100 pA x Vo)	200 V
±1 mA	50 nA	1 nA	±(0.04%+150 nA+1 nA x Vo)	±(0.03%+60 nA+1 nA x Vo)	200 V
±10 mA	500 nA	10 nA	±(0.04%+1.5 µA+10 nA x Vo)	±(0.03%+200 nA+10 nA x Vo)	200 V
±100 mA	5 µA	100 nA	±(0.045%+15 µA+100 nA x Vo)	±(0.04%+6 µA+100 nA x Vo)	³
±1 A	50 µA	1 µA	±(0.4%+300 µA+1 µA x Vo)	±(0.4%+150 µA+1 µA x Vo)	³

- Specified measurement resolution is limited by fundamental noise limits.
- ± (% of read value + offset current (fixed part determined by the output/measurement range + proportional part that is multiplied by Vo))
- 200 V ($I_o \leq 50$ mA), 100 V (50 mA $< I_o \leq 125$ mA), 40 V (125 mA $< I_o \leq 500$ mA), 20 V (500 mA $< I_o \leq 1$ A), I_o is the output current in Amps.

Voltage range, resolution, and accuracy (high speed ADC)

Voltage range	Force resolution	Measure resolution	Force accuracy ¹	Measure accuracy ¹	Maximum current
±2 V	100 µV	100 µV	±(0.018% + 400 µV)	±(0.01% + 700 µV)	1 A
±20 V	1 mV	1 mV	±(0.018% + 3 mV)	±(0.01% + 4 mV)	1 A
±40 V	2 mV	2 mV	±(0.018% + 6 mV)	±(0.015% + 8 mV)	500 mA
±100 V	5 mV	5 mV	±(0.018% + 15 mV)	±(0.02% + 20 mV)	125 mA
±200 V	10 mV	10 mV	±(0.018% + 30 mV)	±(0.035% + 40 mV)	50 mA

1. ± (% of read value + offset voltage V)

Current range, resolution, and accuracy (high speed ADC)

Current range	Force resolution	Measure resolution ¹	Force accuracy ²	Measure accuracy ²	Maximum voltage
±1 nA	50 fA	50 fA	±(0.1%+300 fA+1 fA x Vo)	±(0.25%+300 fA+1 fA x Vo)	200 V
±10 nA	500 fA	500 fA	±(0.1%+3 pA+10 fA x Vo)	±(0.25%+2 pA+10 fA x Vo)	200 V
±100 nA	5 pA	5 pA	±(0.05%+30 pA+100 fA x Vo)	±(0.1%+20 pA+100 fA x Vo)	200 V
±1 µA	50 pA	50 pA	±(0.05%+300 pA+1 pA x Vo)	±(0.1%+200 pA+1 pA x Vo)	200 V
±10 µA	500 pA	500 pA	±(0.05%+3 nA+10 pA x Vo)	±(0.05%+2 nA+10 pA x Vo)	200 V
±100 µA	5 nA	5 nA	±(0.035%+15 nA+100 pA x Vo)	±(0.05%+20 nA+100 pA x Vo)	200 V
±1 mA	50 nA	50 nA	±(0.04%+150 nA+1 nA x Vo)	±(0.04%+200 nA+1 nA x Vo)	200 V
±10 mA	500 nA	500 nA	±(0.04%+1.5 µA+10 nA x Vo)	±(0.04%+2 µA+10 nA x Vo)	200 V
±100 mA	5 µA	5 µA	±(0.045%+15 µA+100 nA x Vo)	±(0.1%+20 µA+100 nA x Vo)	³
±1 A	50 µA	50 µA	±(0.4%+300 µA+1 µA x Vo)	±(0.5%+300 µA+1 µA x Vo)	³

1. Specified measurement resolution is limited by fundamental noise limits.

2. ± (% of read value + offset current (fixed part determined by the output/measurement range + proportional part that is multiplied by Vo))

3. 200 V (Io ≤ 50 mA), 100 V (50 mA < Io ≤ 125 mA), 40 V (125 mA < Io ≤ 500 mA), 20 V (500 mA < Io ≤ 1 A), Io is the output current in Amps.

Power consumption

Voltage source mode

Voltage range	Power
2 V	20 x Ic (W)
20 V	20 x Ic (W)
40 V	40 x Ic (W)

100 V	$100 \times I_c$ (W)
200 V	$200 \times I_c$ (W)

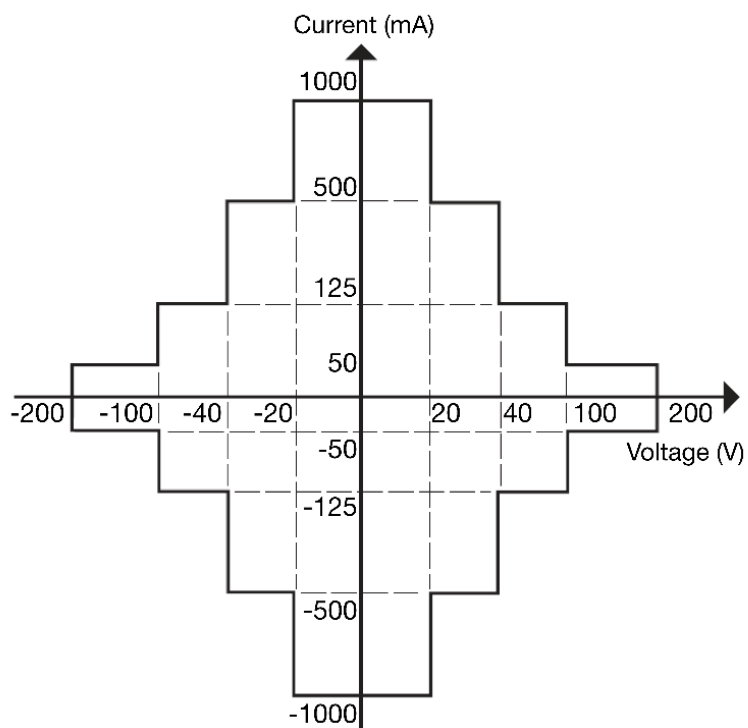
Where I_c is the current compliance setting.

Current source mode

Voltage compliance	Power
$V_c \leq 20$	$20 \times I_o$ (W)
$20 < V_c \leq 40$	$40 \times I_o$ (W)
$40 < V_c \leq 100$	$100 \times I_o$ (W)
$100 < V_c \leq 200$	$200 \times I_o$ (W)

Where V_c is the voltage compliance setting and I_o is output current

HPSMU measurement and output range



MCSMU Module Specifications

Voltage range, resolution, and accuracy

Voltage range	Force resolution	Measure resolution	Force accuracy ¹ ±(% + mV)	Measure accuracy ¹ (% + mV)	Maximum current
±0.2 V	200 nV	200 nV	±(0.06 + 0.14)	±(0.06 + 0.14)	1 A
±2 V	2 µV	2 µV	±(0.06 + 0.6)	±(0.06 + 0.6)	1 A
±20 V	20 µV	20 µV	±(0.06 + 3)	±(0.06 + 3)	1 A
±40 V ²	40 µV	40 µV	±(0.06 + 3)	±(0.06 + 3)	1 A

1. ±(% of reading value + fixed offset in mV).
2. Maximum output voltage is 30 V.

Current range, resolution, and accuracy

Current range	Force resolution	Measure resolution	Force accuracy ¹ (% + A + A)	Measure accuracy ¹ (% + A + A)	Maximum voltage
±10 µA	10 pA	10 pA	±(0.06 + 2E-9 + V _o x 1E-10)	±(0.06 + 2E-9 + V _o x 1E-10)	30 V
±100 µA	100 pA	100 pA	±(0.06 + 2E-8 + V _o x 1E-9)	±(0.06 + 2E-8 + V _o x 1E-9)	30 V
±1 mA	1 nA	1 nA	±(0.06 + 2E-7 + V _o x 1E-8)	±(0.06 + 2E-7 + V _o x 1E-8)	30 V
±10 mA	10 nA	10 nA	±(0.06 + 2E-6 + V _o x 1E-7)	±(0.06 + 2E-6 + V _o x 1E-7)	30 V
±100 mA	100 nA	100 nA	±(0.06 + 2E-5 + V _o x 1E-6)	±(0.06 + 2E-5 + V _o x 1E-6)	30 V
±1 A ²	1 µA	1 µA	±(0.4 + 2E-4 + V _o x 1E-5)	±(0.4 + 2E-4 + V _o x 1E-5)	30 V

1. ±(% of reading value + fixed offset in A + proportional offset in A), V_o is the output voltage in V.
2. Pulse mode only. The maximum value of the base current during pulsing is ±50 mA.

Power consumption

Voltage source mode:

Voltage range	Power
0.2 V	40 x I _c (W)
2 V	40 x I _c (W)
40 V	40 x I _c (W)

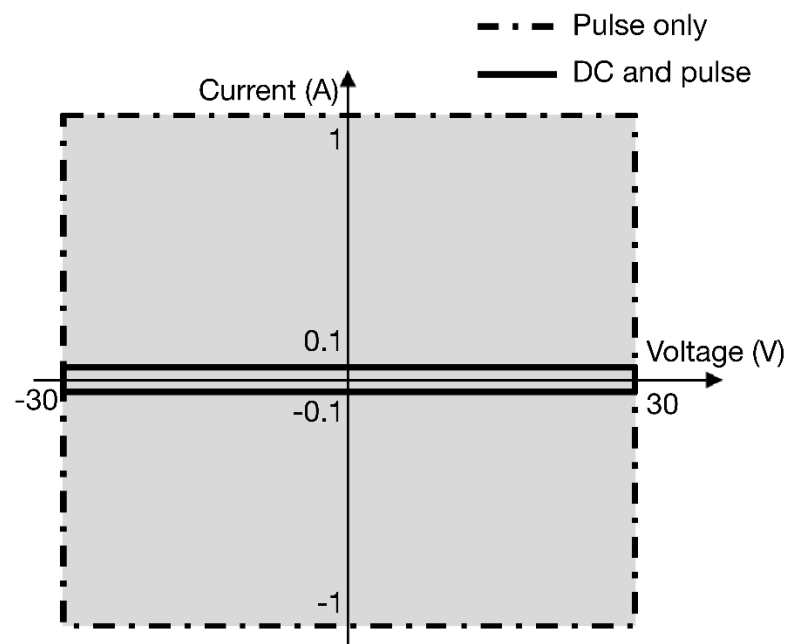
Where I_c is the current compliance setting.

Current source mode

Voltage compliance	Power
$V_c \leq 20$	$40 \times I_o \text{ (W)}$
$0.2 < V_c \leq 2$	$40 \times I_o \text{ (W)}$
$2 < V_c \leq 40$	$40 \times I_o \text{ (W)}$

Where V_c is the voltage compliance setting and I_o is output current

MCSMU measurement and output range



Output terminal/connection

Dual triaxial connector, Kelvin (remote sensing)

Voltage/current compliance (limiting)

The SMU can limit output voltage or current to prevent damaging the device under test.

Voltage:

0 V to ± 100 V (MPSMU, HRSMU)

0 V to ± 200 V (HPSMU)

0 V to ± 30 V (MCSMU)

Current:

± 10 fA to ± 100 mA (HRSMU/MPSMU with ASU)

± 100 fA to ± 100 mA (HRSMU)

± 1 pA to ± 100 mA (MPSMU)

± 1 pA to ± 1 A (HPSMU)

± 10 nA to ± 1 A (MCSMU)

Compliance accuracy:

Same as the current or voltage set accuracy.

About measurement accuracy

RF electromagnetic field and SMU measurement accuracy: SMU voltage and current measurement accuracy can be affected by RF electro-magnetic field strengths greater than 3 V/m in the frequency range of 80 MHz to 1 GHz. The extent of this effect depends upon how the instrument is positioned and shielded.

Induced RF field noise and SMU measurement accuracy: SMU voltage and current measurement accuracy can be affected by induced RF field noise strengths greater than 3 V_{rms} in the frequency range of 150 kHz to 80 MHz. The extent of this effect depends upon how the instrument is positioned and shielded.

Pulse measurement

Programmable pulse width, period and delay:

For HPSMU, MPSMU, and HRSMU

Pulse width: 500 μ s to 2 s

Pulse period: 5 ms to 5 s

Period $\geq$ width + 2 ms (when width $\leq$ 100 ms)

Period $\geq$ width + 10 ms (when width > 100 ms)

Pulse resolution: 100 μ s

Pulse delay: 0 s

For MCSMU

Pulse width:

10 μ s* to 100 ms (1 A range)

10 μ s* to 2 s (10 μ A to 100 mA range)

Pulse width resolution: 2 μ s

Pulse period: 5 ms to 5 s

Pulse period resolution: 100 μ s

Pulse duty:

For 1 A range: $\leq$ 5%

For 10 μ A to 100m A range

Period $\geq$ delay + width + 2 ms (when delay + width $\leq$ 100 ms)

Period $\geq$ delay + width + 10 ms (when delay + width > 100 ms)

Pulse delay: 0 s to (Period–width)

* Recommended pulse width $\geq 50 \mu\text{s}$

Time to reach within 1% of the final value at resistive load $>50 \Omega$, 10 V step voltage, 1 A compliance (supplemental characteristics)

Supplemental Characteristics

Current compliance setting accuracy (for opposite polarity):

For HPSMU, MPSMU, and HRSMU:

For 1 pA to 10 nA ranges: $\pm$ (setting accuracy + 12% of range)

For 100 nA to 1 A ranges: $\pm$ (setting accuracy + 2.5% of range)

For MCSMU: $\pm$ (setting accuracy + 2.5% of range)

SMU pulse setting accuracy (fixed measurement range):

For HPSMU, MPSMU, and HRSMU:

Width: $\pm 0.5\% \pm 50 \mu\text{s}$

Period: $\pm 0.5\% \pm 100 \mu\text{s}$

For MCSMU:

Width: $\pm 0.1\% \pm 2 \mu\text{s}$

Period: $\pm 0.1\% \pm 100 \mu\text{s}$

Minimum pulse measurement time:

16 μs (HPSMU, MPSMU, and HRSMU)

2 μs (MCSMU)

Voltage source output resistance:

(Force line, non-Kelvin connection)

0.2 Ω (HPSMU)

0.3 Ω (MPSMU, HRSMU)

Voltage measurement input resistance:

$\geq 10^{13} \Omega$ (HPSMU, MPSMU, and HRSMU)

$\geq 10^9 \Omega$ (MCSMU, $\leq 1 \text{ A}$)

Current source output resistance:

$\geq 10^{13} \Omega$ (HPSMU, MPSMU, and HRSMU)

$\geq 10^9 \Omega$ (MCSMU, $\leq 1 \text{ A}$)

Maximum allowable cable resistance:

(Kelvin connection)

For HPSMU, MPSMU, and HRSMU:

Sense: 10Ω

Force: 10Ω ($\leq 100 \text{ mA}$), 1.5Ω ($>100 \text{ mA}$)

For MCSMU

Sense: 10Ω

Force : 1Ω

between High and Low

Maximum allowable inductance:

Force $3 \mu\text{H}$ with Low Force as shield (MCSMU)

Maximum load capacitance:

For HPSMU, MPSMU, and HRSMU:

1 pA to 10 nA ranges: 1000 pF

100 nA to 10 mA ranges: 10 nF

100 mA and 1 A ranges: $100 \mu\text{F}$

For MCSMU:

10 μA to 10 mA range : 12 nF

100 mA to 1 A range : $100 \mu\text{F}$

Maximum guard capacitance:

900 pF (HPSMU, MPSMU, and HRSMU)

660 pF (HRSMU/MPSMU with ASU)

Maximum shield capacitance:

5000 pF (HPSMU, MPSMU, and HRSMU)

3500 pF (HRSMU/MPSMU with ASU)

Noise characteristics:

For HPSMU, MPSMU, and HRSMU (filter ON)

Voltage source: 0.01% of V range (rms.)

Current source: 0.1% of I range (rms.)

For MCSMU

Voltage/Current source: 200 mV (0 to peak) max

Overshoot (filter ON):

For HPSMU MPSMU, and HRSMU

Voltage source: 0.03% of V range

Current source: 1% of I range

For MCSMU

Voltage/Current source: 10% of range

Range switching transient noise:

For HPSMU, MPSMU, and HRSMU (filter ON):

Voltage ranging: 250 mV

Current ranging: 70 mV

For MCSMU:

Voltage ranging: 250 mV

Current ranging: 70 mV

Maximum guard offset voltage:

± 1 mV (HPSMU)

± 3 mV (MPSMU, HRSMU)

± 4.2 mV (HRSMU/MPSMU with ASU, $I_{out} \leq 100 \mu A$)

Maximum slew rate:

0.2 V/ μs (HPSMU, MPSMU, and HRSMU)

1 V/ μs (MCSMU)

Maximum DC floating voltage:

± 200 V DC between low force and common (MCSMU)

MFCMU (multi frequency capacitance measurement unit) Module Specifications

Measurement functions

Measurement parameters:

Cp-G, Cp-D, Cp-Q, Cp-Rp, Cs-Rs, Cs-D, Cs-Q, Lp-G, Lp-D, Lp-Q, Lp-Rp, Ls-Rs, Ls-D, Ls-Q, R-X, G-B, Z-q, Y-q

Ranging:

Auto and fixed

Measurement terminal:

Four-terminal pair configuration, four BNC (female) connectors

Cable length:

1.5 m or 3 m, automatic identification of accessories

Test signal

Frequency:

Range: 1 kHz to 5 MHz

Resolution: 1 mHz (minimum)

Accuracy: $\pm 0.008\%$

Output signal level:

Range: 10 mV_{rms} to 250 mV_{rms}

Resolution: 1 mV_{rms}

Accuracy:

$\pm(10.0\% + 1 \text{ mV}_{\text{rms}})$ at the measurement port of the MFCMU

$\pm(15.0\% + 1 \text{ mV}_{\text{rms}})$ at the measurement port of the MFCMU cable (1.5 m or 3.0 m)

Output impedance: 50 Ω , typical

Signal level monitor:

Range: 10 mV_{rms} to 250 mV_{rms}

Accuracy (open load):

$\pm(10.0\% \text{ of reading} + 1 \text{ mV}_{\text{rms}})$ at the measurement port of the MFCMU

$\pm(15.0\% \text{ of reading} + 1 \text{ mV}_{\text{rms}})$ at the measurement port of the MFCMU cable (1.5 m or 3 m)

DC bias function

DC bias:

Range: 0 to $\pm 25 \text{ V}$

Resolution: 1 mV

Accuracy: $\pm(0.5\% + 5.0 \text{ mV})$ at the measurement port of the MFCMU or the MFCMU cable (1.5 m or 3.0 m)

Maximum DC bias current (supplemental characteristics)

Impedance range	Maximum DC bias current
50 Ω	10 mA
100 Ω	10 mA
300 Ω	10 mA
1 k Ω	1 mA
3 k Ω	1 mA
10 k Ω	100 μ A
30 k Ω	100 μ A
100 k Ω	10 μ A
300 k Ω	10 μ A

Output impedance: 50 Ω , typical

DC bias monitor:

Range: 0 to ± 25 V

Accuracy (open load):

$\pm(0.2\%$ of reading + 10.0 mV) at the measurement port of the MFCMU or the MFCMU cable (1.5 m or 3.0 m)

Sweep characteristics

Available sweep parameters:

Oscillator level, DC bias voltage, frequency

Sweep type: linear, log

Sweep mode: single, double

Sweep direction: up, down

Number of measurement points:

Maximum 1001 points

Measurement accuracy

The following parameters are used to express the impedance measurement accuracy at the measurement port of the MFCMU or the MFCMU cable (1.5 m or 3.0 m).

Z_x : Impedance measurement value (Ω)

D_x : Measurement value of D

$E = E_P' + (Z_S'/|Z_x| + Y_O'|Z_x|) \times 100$ (%)

$E_P' = E_{PL} + E_{POSC} + E_P$ (%)

$$Y_O' = Y_{OL} + Y_{OSC} + Y_O \text{ (S)}$$

$$Z_S' = Z_{SL} + Z_{OSC} + Z_S \text{ (}\Omega\text{)}$$

|Z| accuracy

$$\pm E \text{ (%)}$$

θ accuracy

$$\pm E/100 \text{ (rad)}$$

C accuracy

$$\text{at } D_x \leq 0.1$$

$$\pm E \text{ (%)}$$

$$\text{at } D_x > 0.1$$

$$\pm E \times (\sqrt{1+D_x^2}) \text{ (%)}$$

D accuracy

$$\text{at } D_x \leq 0.1$$

$$\pm E/100$$

$$\text{at } D_x > 0.1$$

$$\pm E \times (1 + D_x)/100$$

G accuracy

$$\text{at } D_x \leq 0.1$$

$$\pm E / D_x \text{ (%)}$$

$$\text{at } D_x > 0.1$$

$$\pm E \times (\sqrt{1+D_x^2}) / D_x \text{ (%)}$$

Note: measurement accuracy is specified under the following conditions:

Temperature: 23°C $\pm$ 5°C

Integration time: 1 PLC or 16 PLC

Parameters E_{posc} Z_{osc}

Oscillator level	E_{posc} (%)	Z_{osc} (m Ω)
125 mV < $V_{osc} \leq 250$ mV	$0.03 \times (250 / V_{osc} - 1)$	$5 \times (250 / V_{osc} - 1)$
64 mV < $V_{osc} \leq 125$ mV	$0.03 \times (125 / V_{osc} - 1)$	$5 \times (125 / V_{osc} - 1)$
32 mV < $V_{osc} \leq 64$ mV	$0.03 \times (64 / V_{osc} - 1)$	$5 \times (64 / V_{osc} - 1)$
$V_{osc} \leq 32$ mV	$0.03 \times (32 / V_{osc} - 1)$	$5 \times (64 / V_{osc} - 1)$

V_{osc} is oscillator level in mV.

Parameters E_{PL} Y_{OL} Z_{SL}

Cable length	E_{PL} (%)	Y_{OL} (nS)	Z_{SL} (m Ω)
1.5 m	$0.02 + 3 \times f/100$	$750 \times f/100$	5.0
3 m	$0.02 + 5 \times f/100$	$1500 \times f/100$	5.0

f is frequency in MHz. If measurement cable is extended, open compensation, short compensation, and load compensation must be performed.

Parameters E_P Y_{Osc} Y_O Z_S

Frequency	E_P (%)	Y_{Osc} (nS)	Y_O (nS)	Z_S (m Ω)
$1 \text{ kHz} \leq f \leq 200 \text{ kHz}$	0.095	$1 \times (125/ V_{Osc} - 0.5)$	1.5	5.0
$200 \text{ kHz} < f \leq 1 \text{ MHz}$	0.095	$2 \times (125/ V_{Osc} - 0.5)$	3.0	5.0
$1 \text{ MHz} < f \leq 2 \text{ MHz}$	0.28	$2 \times (125/ V_{Osc} - 0.5)$	3.0	5.0
$2 \text{ MHz} < f$	0.28	$20 \times (125/ V_{Osc} - 0.5)$	30.0	5.0

f is frequency in Hz.

V_{Osc} is oscillator level in mV.

Example of calculated C/G measurement accuracy

Frequency	Measured capacitance	C accuracy ¹	Measured conductance	G accuracy ¹
5 MHz	1 pF	$\pm 0.61\%$	$\leq 3 \mu\text{S}$	$\pm 192 \text{ nS}$
	10 pF	$\pm 0.32\%$	$\leq 31 \mu\text{S}$	$\pm 990 \text{ nS}$
	100 pF	$\pm 0.29\%$	$\leq 314 \mu\text{S}$	$\pm 9 \mu\text{S}$
	1 nF	$\pm 0.32\%$	$\leq 3 \text{ mS}$	$\pm 99 \mu\text{S}$
1 MHz	1 pF	$\pm 0.26\%$	$\leq 628 \text{ nS}$	$\pm 16 \text{ nS}$
	10 pF	$\pm 0.11\%$	$\leq 6 \mu\text{S}$	$\pm 71 \text{ nS}$
	100 pF	$\pm 0.10\%$	$\leq 63 \mu\text{S}$	$\pm 624 \text{ nS}$
	1 nF	$\pm 0.10\%$	$\leq 628 \mu\text{S}$	$\pm 7 \mu\text{S}$
100 kHz	10 pF	$\pm 0.18\%$	$\leq 628 \text{ nS}$	$\pm 11 \text{ nS}$
	100 pF	$\pm 0.11\%$	$\leq 6 \mu\text{S}$	$\pm 66 \text{ nS}$
	1 nF	$\pm 0.10\%$	$\leq 63 \mu\text{S}$	$\pm 619 \text{ nS}$
	10 nF	$\pm 0.10\%$	$\leq 628 \mu\text{S}$	$\pm 7 \mu\text{S}$

10 kHz	100 pF	±0.18%	≤ 628 nS	±11 nS
	1 nF	±0.11%	≤ 6 μS	±66 nS
	10 nF	±0.10%	≤ 63 μS	±619 nS
	100 nF	±0.10%	≤ 628 μS	±7 μS
1 kHz	100 pF	±0.92%	≤ 63 nS	±6 nS
	1 nF	±0.18%	≤ 628 nS	±11 nS
	10 nF	±0.11%	≤ 6 μS	±66 nS
	100 nF	±0.10%	≤ 63 μS	±619 nS

1. The capacitance and conductance measurement accuracy is specified under the following conditions:
 $D_x = 0.1$
Integration time: 1 PLC
Test signal level: 30 mV_{rms}
At four-terminal pair port of MFCMU

Atto-sense and switch unit (ASU) Specifications

AUX path specification

Maximum voltage

- 100 V (AUX input to AUX common)
- 100 V (AUX input to circuit common)
- 42 V (AUX common to circuit common)

Maximum current

- 0.5 A (AUX input to force output)

ASU supplemental characteristics

Band width (at -3 dB)

- 30 MHz (AUX port)

SMU CMU unify unit (SCUU) and Guard Switch Unit (GSWU) Specifications

The SCUU multiplexes the outputs from two SMUs (MPSMUs and/or HRSMUs) and the CMU. The SCUU outputs are two sets of Kelvin triaxial ports (Force and Sense). The SCUU also allows the SMUs to act as DC bias sources in conjunction with the CMU. Special cables are available to connect the SMUs and CMU with the SCUU, and an auto-detect feature automatically compensates for the cable length going to the SCUU.

The GSWU contains a relay that automatically opens for IV measurements and closes for CV measurements, forming a guard return path to improve CV measurement accuracy.

Supported SMU

MPSMU and HRSMU

For SCUU

Inputs:

Triaxial ports: Force1, Sense1, Force2, and Sense2

BNC ports: for MFCMU

Control port: for MFCMU

Outputs:

Triaxial ports: Force1/CMUH, Sense1, Force2/CMUL, and Sense2

Control port: for GSWU

LEDs: SMU/CMU output status indicator

Docking mode:

Direct and indirect mode

For GSWU

Input:

Control port: for SCUU

Mini pin plug ports: Guard1, Guard2

Output:

LED: Connection status indicator

SCUU supplemental characteristics SMU path:

Offset current:

$< \pm (20 \text{ fA} + 0.004\% \text{ of SMU current range})$ (1 pA to 1 μA range)

Offset current is negligible for other current ranges

Offset voltage: $< 100 \mu\text{V}$ at 300 sec

Closed channel residual resistance: $< 200 \text{ m}\Omega$

Channel isolation resistance: $> 10^{15} \Omega$

CMU path:

Test signal

Signal output level additional errors (CMU bias, open load):

$\pm 2\%$ (direct docking)

$\pm 7\%$ (indirect docking)

Signal output level additional errors (SMU bias, open load):

±5% (direct docking, ≥ 10 kHz)

±10% (indirect docking, ≥ 10 kHz)

Output impedance: 50 Ω, typical

Signal level monitor additional errors (open load):

±2% (CMU bias), direct docking

±5% (SMU bias), direct docking

±7% (CMU bias), indirect docking

±10% (SMU bias), indirect docking

DC bias function

DC voltage bias (CMU bias):

Range: 0 to ±25 V

Resolution: 1 mV

Additional errors (for CMU bias): ±100 µV (open load)

DC voltage bias (SMU bias):

Range: 0 to ±100 V

Resolution: 5 mV

Additional errors (for SMU voltage output accuracy):

±100 µV (open load)

DC bias monitor additional errors (open load):

±20 mV, direct docking

±30 mV, indirect docking

Output impedance:

50 Ω, typical

DC output resistance: 50 Ω (CMU bias), 130 Ω (SMU bias)

Measurement accuracy

Impedance measurement error is given by adding the following additional error E_e to the MFCMU measurement error.

$$E_e = \pm(A + Z_s/|Z_x| + Y_o|Z_x|) \times 100 (\%)$$

Z_x : Impedance measurement value (Ω)

A: 0.05% (direct docking) or 0.1% (indirect docking)

Z_s : 500 + 500 × f (mΩ)

Y_o : 1 + 1000 × f/100 (nS) (direct docking, x2 for indirect docking)

Note: f is frequency in MHz

When the measurement terminals are extended by using the measurement cable, the measurement accuracy is applied to the data measured after performing the open/short/load correction at the DUT side cable end.

Note: The error is specified under the following conditions:

Temperature: 23°C ±5°C

Integration time: 1 PLC or 16 PLC

HV-SPGU (high voltage semiconductor pulse generator unit) Module Specification

Specifications

Number of output channels:

2 channels per module

Modes: pulse, constant, and freerun

Standard pulse mode:

- Two level pulse
- Three level pulse per one channel
- Pulse period: 20 ns to 10 s

Delay range: 0 s to 9.99 s

Delay resolution: 2.5 ns (minimum)

Output count: 1 to 1,000,000

Voltage monitor minimum sampling period: 5 µs

Trigger output:

Level: TTL

Timing: Synchronized with pulse period

Trigger width:

Pulse period x 1/2 (pulse period ≤ 10 µs)

Maximum 5 µs (pulse period > 10 µs)

Pulse/DC output voltage and accuracy

Output voltage (V_{out})	50 Ω load	–20 V to +20 V
	Open load	–40 V to +40 V
Accuracy ¹	Open load	±(0.5% + 50 mV)
Amplitude resolution	50 Ω load	0.2 mV ($ V_{out} \leq 5V$) 0.8 mV ($5V < V_{out} \leq 20V$)
	Open load	0.4 mV ($ V_{out} \leq 10V$) 1.6 mV ($10V < V_{out} \leq 40V$)

Output connectors	SMA
Source impedance	50 Ω^2
Short circuit current	800 mA peak (400 mA average ³)
Overshoot/pre-shoot/ringing ⁴ 50 Ω load	$\pm(5\% + 20 \text{ mV})$

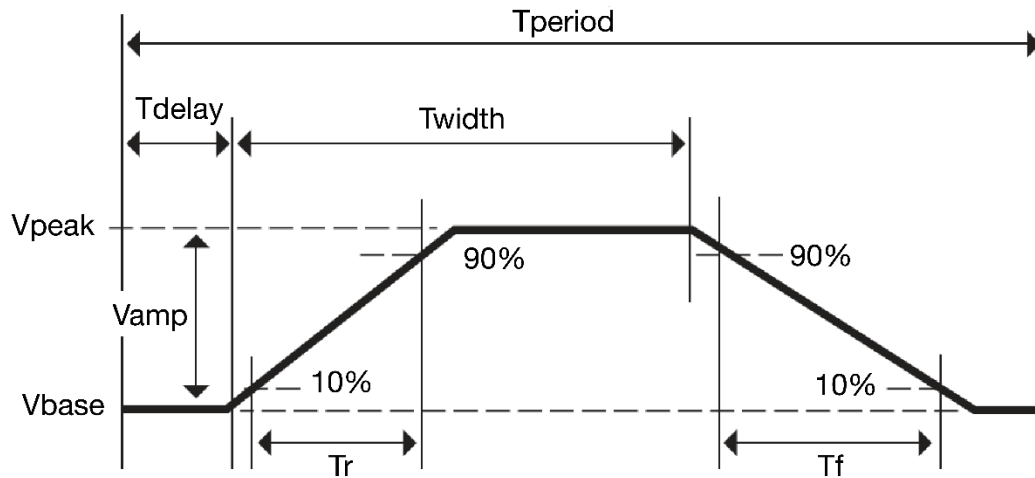
1. At 1 μs after completing transition.
2. Supplemental characteristics ($\pm 1\%$)
3. This value is specified under the following condition: [(Number of installed HV-SPGUs) x 0.2 A] + [DC current output by all modules (including HV-SPGUs)] < 3.0 A
4. Follow the specified condition of the transient time.

Pulse range and pulse parameter¹

Frequency range		0.1 Hz to 33 MHz
Pulse period	Programmable range	20 ns to 10 s
	Resolution	10 ns
	Minimum ⁴	100 ns ³
	Accuracy	$\pm 1\%$ ($\pm 0.01\% + 200 \text{ ps}$) ²
Width	Programmable range	10 ns to (period – 10 ns)
	Resolution	2.5 ns (T_r and $T_f \leq 8 \mu\text{s}$) 10 ns (T_r or $T_f > 8 \mu\text{s}$)
	Minimum ⁴	50 ns (25 ns typical) ³
	Accuracy	$\pm(3\% + 2 \text{ ns})$
Transition time ⁵ (T_r and T_f)	Programmable range	8 ns to 400 ms
	Resolution	2 ns (T_r and $T_f \leq 8 \mu\text{s}$) 8 ns (T_r or $T_f > 8 \mu\text{s}$)
	Minimum ⁴	15 ns ² ($V_{amp} \leq 10 \text{ V}$) 20 ns ($V_{amp} \leq 10 \text{ V}$) 30 ns ($V_{amp} \leq 20 \text{ V}$) 60 ns ($V_{amp} > 20 \text{ V}$)
	Accuracy	-5% to $5\% + 10 \text{ ns}$ ($V_{amp} \leq 10 \text{ V}$) -5% to $5\% + 20 \text{ ns}$ ($V_{amp} \leq 20 \text{ V}$)
Output relay switching time ⁶	Open/close	100 μs ²

1. Unless otherwise stated, all specifications assume a 50 Ω termination.
2. Supplemental characteristics.
3. This is specified at $V_{amp} \leq 10 \text{ V}$.
4. Minimum value in which timing accuracy can be applied.
5. The time from 10% to 90% of V_{amp} which is the amplitude of output pulse.
6. Solid state relay for frequent switching applications.

Definition of pulse waveform



SPGU supplemental characteristics

Pulse width jitter: 0.001% +150 ps

Pulse period jitter: 0.001% +150 ps

Maximum slew rate: 1000 V/ μ s (50 Ω load)

Noise: 10 mV_{rms} (at DC output)

Advanced feature:

Voltage monitor: The HV-SPGU has a voltage monitor function to measure the voltage at the DUT terminal.

Measurement accuracy (open load): $\pm(0.1\%$ of reading +25 mV)

Measurement resolution: 50 μ V

Note: Specified at 1 PLC (20 ms = (5 μ s sample + 5 μ s interval) x 2000 samples.)

Voltage compensation: The HV-SPGU can measure the impedance of DUT and adjust the output voltage according to the DUT impedance.

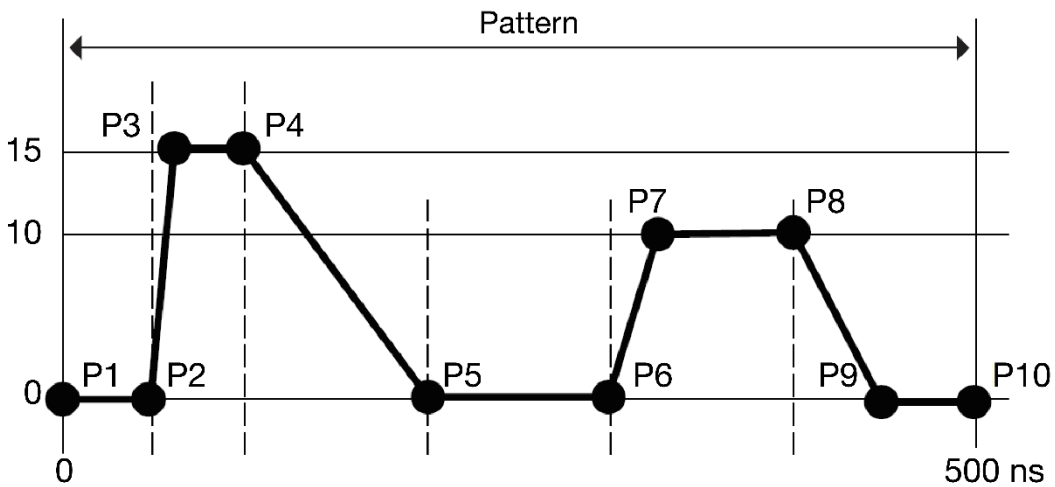
ALWG (arbitrary linear waveform generator) function

Arbitrary linear waveform generator (ALWG) mode:

- Output complex waveform per one channel of HV-SPGU
- Define multi-level pulse and multi-pulse waveform including open state pulse with ALWG GUI editor

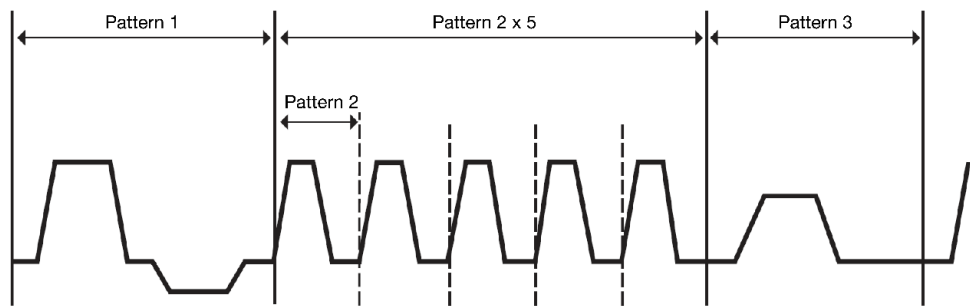
- Sequential pulse waveform from user-defined pulse waveform
- 1024 points per one channel
- Programmable timing range: 10 ns to 671.088630 ms, 10 ns resolution

Example 1. ALWG setup table and pattern



Point	Time	Voltage
1	0	0.0 V
2	50 ns	0.0 V
3	70 ns	15.0 V
4	100 ns	15.0 V
5	200 ns	0.0 V
6	300 ns	0.0 V
7	320 ns	10.0 V
8	400 ns	10.0 V
9	450 ns	0.0 V
10	500 ns	0.0 V

Example 2. ALWG complex waveform



16440A SMU/pulse generator selector

The Keysight 16440A SMU/pulse generator selector switches either a SMU or PGU to the associated output port. You can expand to four channels by adding an additional 16440A. The PGU port on channel 1 provides a “PGU OPEN” function, which can disconnect the PGU by opening a semiconductor relay. The Keysight B1500A and 16445A are required to use the 16440A.

The following specifications data is specified at 23°C ± 5°C and 50% relative humidity.

- Channel configuration:
2 channels (CH 1 and CH 2).
Can add an additional 2 channels (CH 3 and CH 4) by adding another 16440A (selector expander)

	Input	Output
Channel 1 (CH 1)	2 (SMU and PGU ¹)	1
Channel 2 (CH 2)	2 (SMU and PGU)	1
Channel 3 (CH 3) ²	2 (SMU and PGU ¹)	1
Channel 4 (CH 4) ²	2 (SMU and PGU)	1

1. PGU channels 1 & 3 have a built-in series semiconductor relay.
2. Available when a second 16440A (selector expander) is installed.

- Voltage and current range

Input port	Maximum voltage	Maximum current
SMU	200 V	1.0 A
PGU	40 V	0.4 A ¹

1. This is peak-to-peak current.

16445A SMU/PGU selector connection adaptor

The Keysight 16445A selector adapter is required to control and to supply DC power to the Keysight 16440A SMU/pulse generator selector.

Power requirement: 100 to 240 V, 50/60 Hz

Maximum volt-amps (VA): 20 VA

WGFMU (waveform generator/fast measurement unit) Module Specification

Overview

The WGFMU is a self-contained module offering the combination of arbitrary linear waveform generation (ALWG) with synchronized fast current or voltage (IV) measurement. The ALWG function allows you to generate not only DC, but also various types of AC waveforms. In addition to this versatile sourcing capability, the WGFMU can also perform measurement in synchronization with the applied waveform, which enables accurate high-speed IV characterization.

Measurement mode, function and range

WGFMU Mode	WGFMU function			Voltage force ranges	Voltage measurement ranges	Current measurement ranges	Source Impedance	Maximum output
	VF	VM	IM					
Fast IV mode/ DC mode	Y	Y	Y	-3 V to +3 V -5 V to +5 V -10 V to 0 V 0 V to +10 V	5 V 10 V	1 μ A, 10 μ A, 100 μ A, 1mA, 10 mA	0 Ω ¹	+10 V, -10 V, $\pm$ 5 V
PG mode	Y	Y	–	-3 V to +3 V -5 V to +5 V	5 V	–	50 Ω ²	$\pm$ 5 V (open load) $\pm$ 2.5 V (50 Ω load)
SMU pass-through	Measurement is performed by an SMU			–	–	–	–	$\pm$ 25 V $\pm$ 100 mA

VF: Voltage Force VM: Voltage Measurement IM: Current Measurement

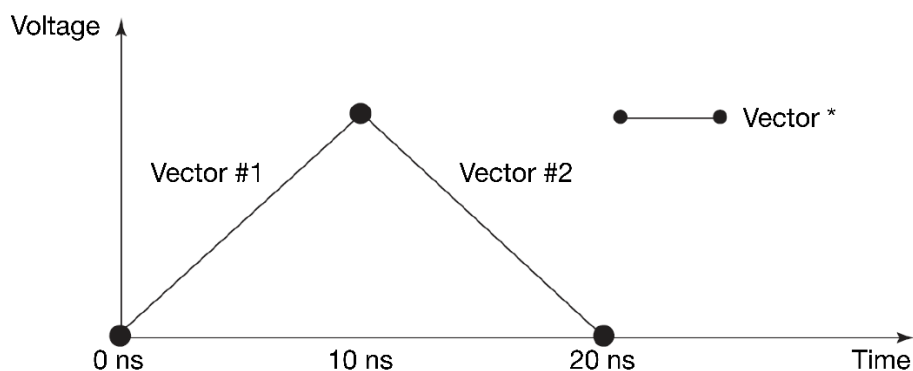
1. Fast IV mode supports active analog feedback loop to keep its output as specified voltage and the output impedance negligible. It can reduce the influence of load line effect by the source impedance and DUT impedance.
2. 50 Ω (nominal) at DC in PG mode

Waveform generation and measurement capabilities

Pulse and any waveform can be generated by using ALWG (Arbitrary Linear Waveform Generation) vector data. Measurements can be performed by measurement events embedded on the vectors.

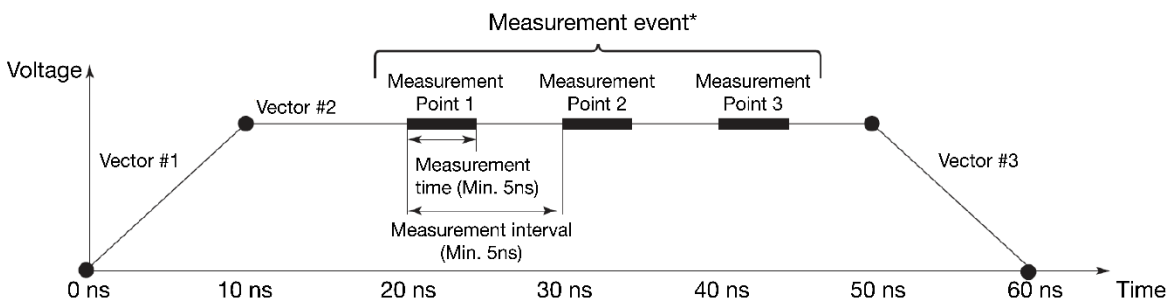
Voltage waveform output	Waveform programming Any waveform (including pulse shape) pattern can be programmed by using ALWG vector data within maximum number of vectors.	Minimum timing resolution	10 ns
		Vector length	10 ns to 10,000 s with 10 ns resolution/vector
		Maximum number of vectors	2048
		Maximum number of sequences	512
		Maximum number of loop counts	10 ¹²
Measurement capabilities	Measurement (event) Measurement can be performed at any specified points/timing in the waveform by using the measurement event feature. This provides the flexibility to perform the measurement only specific area to reduce the data size and utilize the memory efficiently. Measurement events can be embedded on any ALWG vectors in the waveform with number of measurement points, measurement interval and averaging parameters settings.	Sampling rate	200MSa/s
		Maximum number of measurement points	About 4 M data points/channel (typical)
		Interval between measurement points	5 ns, or 10 ns to 1 s with 10 ns resolution
		Averaging per a measurement point	10 ns to 20 ms with 10 ns resolution
		Range change (Event) Current measurement range can be changed at any specified points/timing in the waveform by using the range change event feature. It enables to use the user specified ranges in a measurement sequence according to the device impedance.	
Trigger capability	Trigger out (Event) Output trigger event can be set at any specified points/timing in the waveform by using the trigger out event feature.		

Example 1. Waveform creation by vector data



(*) The waveform is created by specifying multiple vectors (time, voltage). Each vector can be set within the ranges of vector length and voltage.

Example 2. Measurement event on a created waveform



(*) As well as the measurement event, the range change and trigger event can be specified in the vector.

To perform accurate measurement, it is necessary to take the voltage/current settling time into account from the analog performance viewpoint. Refer to the Minimum timing parameters tables as supplemental characteristics of analog performance.

Force, measurement and timing specifications

Voltage force	Accuracy	$\pm (0.1\% \text{ of setting} + 0.1\% \text{ of range})^1$
	Resolution ²	96 μV (-3 to 3 V range) 160 μV (all ranges except for -3 V to 3 V range)
	Overshoot/undershoot	$\pm(5\%+20 \text{ mV})^3$
	Noise	Maximum 0.1 mV_{rms} ⁴
Voltage measurement	Accuracy	$\pm(0.1\% \text{ of reading} \pm 0.1\% \text{ of range})^8$
	Resolution ⁹	680 μV (-5 V to +5 V range) 1.4 mV (-10 V to +10 V range)
	Noise ¹⁰	Maximum 4 mV_{rms} (-5 V to +5 V range)
Current measurement	Accuracy	$\pm(0.1\% \text{ of reading} \pm 0.2\% \text{ of range})^8$
	Resolution ⁹	0.014% of range
	Noise (Effective resolution)	Maximum 0.2% of range ¹¹
Timing accuracy	Rise time T_{rise} (10 to 90%)/ Fall time T_{fall} (90 to 10%)	-5% to (+5% +10 ns) of setting ⁵
	Pulse period	$\pm 1\%$ of setting ⁶
	Pulse width	$\pm(3\% + 2 \text{ ns})^7$

1. Independent of the range or the mode. DC constant voltage output. Load impedance must be $\geq 1 \text{ M}\Omega$ (1 μA range) or $\geq 200 \text{ k}\Omega$ (all other current ranges) for Fast IV mode, or $\geq 1 \text{ M}\Omega$ for PG mode.
2. Can vary at most 5% based on the result of calibration.
3. PG mode, 50 Ω load, T_{rise} and $T_{\text{fall}} > 16 \text{ ns}$ with the 1.5 m cable, $> 32 \text{ ns}$ with 3 m cable, or $> 56 \text{ ns}$ with 5 m cable.

4. Theoretical value for observed time 100 ns to 1 ms, supplemental characteristics.
5. PG mode, 50 Ω load, T_{rise} and $T_{fall} \geq 24$ ns.
6. PG mode, 50 Ω load, pulse period ≥ 100 ns.
7. PG mode, 50 Ω load, pulse width ≥ 50 ns.
8. Independent of the range or the mode. DC constant voltage output. Applicable condition: 10,000 averaging samples for 10 μ A range and above; 100,000 averaging samples for the 1 μ A range.
9. Display resolution. Can vary at most 5% based on the result of calibration.
10. 0 V output, open load, no averaging. Maximum 1.5 mV_{rms} as supplemental characteristics.
11. Effective value at 0 V output, open load, and no averaging. Supplemental characteristics.

Other Specifications

Number of output channels: 2 channels per module

RSU:

Output Connector: SMA

V monitor terminal:

- Connector: BNC
- Source Impedance: 50 Ω (nominal) at DC
- The terminal outputs a buffered signal equal to 1/10 of V_{out} (into a 50 Ω load)

RSU SMU path:

- Leak current: <100 pA (supplemental characteristics)
- Residual resistance: <300 m Ω (supplemental characteristics)

WGFMU to RSU cable length:

The WGFMU and RSU are connected by a special composite cable. The following configurations are available:

- 3 m
- 5 m
- 1.5 m
- 2.4 m + connector adapter + 0.6 m
- 4.4 m + connector adapter + 0.6 m

Note: The connector adapter is used when routing the cable through the prober's connector panel.

Trigger output

Level: TTL

Trigger width: 10 ns

Trigger output skew: <3 ns (supplemental characteristics)

Jitter:

<1 ns (supplemental characteristics)

Skew between channels:

<3 ns, under no electrostatic discharge condition (supplemental characteristics).

Current range change time:

<150 μ s*

* The time until the measured current settles within $\pm 0.3\%$ of the final result value after the range change (supplemental characteristics).

Minimum timing parameters for current measurement (Supplemental Characteristics)¹

Voltage applied to DUT		10 V					
Current applied to DUT		100 nA	1 μ A	10 μ A	100 μ A	1 mA	10 mA
Applied voltage condition	Recommended minimum pulse width ²	47 μ s	38.7 μ s	6.8 μ s	950 ns	240 ns	145 ns
Current measurement condition	Measurement Range	1 μ A	1 μ A	10 μ A	100 μ A	1 mA	10 mA
	Recommended minimum measurement window	10 μ s	1.64 μ s	1 μ s	130 ns	40 ns	20 ns
	Settling time ³	37 μ s	37 μ s	5.8 μ s	820 ns	200 ns	125 ns
	Noise (rms) ⁴	160 pA	425 pA	2.5 nA	47 nA	280 nA	1.9 μ A

1. Measurement conditions: The DUT is a resistive load chosen to adjust the flowing current to the specified current in the table above. The capacitance of the cable between the RSU and the DUT is 20 pF. Voltage is applied to the DUT by a channel of WGFMU/RSU in Fast IV mode and in the 10 mA range, and current measurement is performed by another channel at 0 V in Fast IV mode.
2. Recommended minimum pulse width = settling time + recommended minimum measurement window.
3. The time until the measured value settles to within $\pm 0.6\%$ of the final result value after the output voltage is changed from the initial value (0 V). Minimum rise/fall time of 70 ns is recommended for minimizing overshoot.
4. RMS noise measured over the recommended minimum measurement window.

Minimum timing parameters for voltage measurement (Supplemental Characteristics)¹

Voltage applied to DUT		5V	10 V
Applied voltage condition	Recommended minimum pulse width ²	105 ns	130 ns
Voltage measurement condition	Measurement Range	5 V	10 V
	Recommended minimum measurement window	20 ns	20 ns
	Settling time ³	85 ns	110 ns
	Noise (rms) ⁴	1.4 mV	1.4 mV

1. Measurement conditions: The DUT is a resistive load between 1 k Ω and 10 M Ω . The capacitance of the cable between the RSU and the DUT is 20 pF. Voltage is applied to the DUT by a channel of WGFMU/RSU, and voltage measurement is performed by the same channel. (PG mode for 5 V, Fast IV mode for 10 V)
2. Recommended minimum pulse width = settling time + recommended minimum measurement window.
3. The time until the measured value settles to within $\pm 0.6\%$ of the final result value after the output voltage is changed from the initial value (0 V). Minimum rise/fall time of 70 ns for 10 V, or 30ns for 5 V is recommended for minimizing overshoot.
4. RMS noise measured over the recommended minimum measurement window.

WGFMU Software

Application Programming Interface (API):

Instrument Library (.DLL/.Lib for .NET)

Note: Instrument library is available for the following programming environments. Microsoft Visual C++ .NET, Visual C# .NET, Visual Basic .NET, Visual Basic 6.0, VBA, or TransEra HTBasic for Windows (release 8.3 or later)

Application Tests

- BTI (NBTI/PBTI)
- Sweep/pulsed sweep measurement (using 2ch of WGFMU in fast IV mode)
- Pattern Editor for general purpose

Sample application programs

Following application programs are available on external Windows PC. The Source code is available for customization.

- BTI (NBTI/PBTI)
- Fast IV Sweep
- Pulsed IV measurement
- Transient I/V measurement
- Sampling measurement and RNT data analysis tool

WGFMU supported probe vendors

- Cascade Microtech (Suss MicroTec included.)
- Vector Semiconductor

General specifications

Temperature range

Operating: +5°C to +40°C

Storage: -20°C to +60°C

Humidity range

Operating: 20% to 70% RH, non-condensing

Storage: 10% to 90% RH, non-condensing

Altitude

Operating: 0 m to 2,000 m (6,561 ft)

Storage: 0 m to 4,600 m (15,092 ft)

Power requirement

AC voltage: 100-240 V ($\pm 10\%$)

Line frequency: 50/60 Hz

Maximum volt-amps (VA)

B1500A: 900 VA

Regulatory compliance

EMC:

IEC61326-1/EN61326-1

AS/NZS CISPR 11

KC: RRA Notification amending Radio

Waves Act Article 58-2

Safety:

IEC61010-1/EN61010-1

CAN/CSA-C22.2 No. 61010-1-04, C/US

Certification

CE, cCSAus, C-Tick, KC

Dimensions

B1500A: 420 mm W x 330 mm H x 575 mm D

N1301A-100 SMU CMU unify unit (SCUU): 148 mm W x 75 mm H x 70 mm D

N1301A-200 guard switch unit (GSWU): 33.2 mm W x 41.5 mm H x 32.8 mm D

E5288A Atto-sense and switch unit (ASU): 132 mm W x 88.5 mm H x 50 mm D

B1531A RSU: 45.2 mm W x 70 mm H x 82 mm D

N1255A 2 channel connection box for MCSMU: 184.4 mm W x 61.6 mm H x 169.6 mm D

16440A SMU/PGU selector: 250 mm W x 50 mm H x 275 mm D

16445A Selector adaptor: 250 mm W x 50 mm H x 260 mm D

Weight

B1500A mainframe: 20 kg

B1510A HPSMU: 2.0 kg

B1511B MPSMU: 1.0 kg

B1514A MCSMU: 1.3 kg

B1517A HRSMU: 1.2 kg

B1520A MFCMU: 1.5 kg

B1525A HV-SPGU: 1.3 kg

B1530A WGFMU: 1.3 kg

B1531A RSU: 0.13 kg

E5288A ASU: 0.5 kg

N1301A-100 SCUU: 0.8 kg

N1301A-200 GSWU: 0.1 kg

N1255A 2 channel connection box for MCSMU: 0.7 kg

16440A SMU/PGU selector: 1.1 kg

16445A Selector adapter: 1.0 kg

Keysight EasyEXPERT group+ Software

Keysight EasyEXPERT group+ GUI based characterization software is available either on the B1500A's embedded Windows 10 platform with 15-inch touch screen or on your PC to accelerate the characterization tasks. It supports efficient and repeatable device characterization in the entire characterization process from measurement setup and execution to analysis and data management either interactive manual operation or automation across a wafer in conjunction with a semiautomatic wafer prober. EasyEXPERT group+ makes it easy to perform complex device characterization immediately with the hundreds of ready-to-use measurements (application tests) furnished, and allows you the option of storing test condition and measurement data automatically after each measurement in a

unique built-in database (workspace), ensuring that valuable information is not lost and that measurements can be repeated at a later date. Finally, EasyEXPERT has built-in analysis capabilities and a graphical programming environment that facilitate the development of complex testing algorithms.

Key features

- Multiple measurement modes for quick setup and measurement execution (application test, classic test, tracer test, quick test and oscilloscope view)
- Graphical display, automated analysis capabilities and data generation to Excel and image for analysis and reporting
- Built-in database (workspace) records test data automatically and simplifies the data management without numerous data files
- GUI-based control of the Keysight B2200A, B2201A and E5250A switching matrices
- GUI-based self-test, self-calibration and diagnostics menu for hardware maintenance
- EasyEXPERT remote control function supports the remote measurement execution of application tests that are created on GUI interactively, via the LAN interface
- Data back capability and various data protection feature for shared usage by multiple users
- Characterization environment is available either on mainframe (embedded Windows 10) or on user's PC as a personal and portable analyzer environment. EasyEXPERT group+ can be installed on any PC as many as needed without additional charge.

Application library

EasyEXPERT comes with over 300 application tests conveniently organized by device type, application, and technology. You can easily edit and customize the furnished application tests to fit your specific needs. Application tests are provided for the following categories; they are subject to change without notice.

Device Type	Application Tests
CMOS Transistor	Id-Vg, Id-Vd, Vth, breakdown, capacitance, QSCV, etc.
Bipolar Transistor	Ic-Vc, diode, Gummel plot, breakdown, hfe, capacitance, etc.
Discrete device	Id-Vg, Id-Vd, Ic-Vc, diode, etc.
Memory	Vth, capacitance, endurance test, etc.
Power device	Pulsed Id-Vg, pulsed Id-Vd, breakdown, etc.
Nano Device	Resistance, Id-Vg, Id-Vd, Ic-Vc, etc.
Reliability test	NBTI/PBTI, charge pumping, electro migration, hot carrier injection, J-Ramp, TDDB, etc.
And more	And more

Measurement modes and functions

Operation Mode

Application test mode

The application test mode provides application oriented point-and-click test setup and execution. An application test can be selected from the library by device type and desired measurement, and then executed after modifying the default input parameters as needed.

Classic test mode

The classic test mode provides function oriented test setup and execution with the same look, feel, and terminology of the 4155/4156 user interface. In addition, it improves the 4155/4156 user interface by taking full advantage of EasyEXPERT's GUI features.

Tracer test mode

The tracer test mode offers intuitive and interactive sweep control using a rotary knob similar to a curve tracer. Just like an analog curve tracer, you can sweep in only one direction (useful for R&D device analysis) or in both directions (useful in failure analysis applications). Test set ups created in tracer test mode can be seamlessly and instantaneously transferred to classic test mode for further detailed measurement and analysis.

Oscilloscope view (available for MCSMU)

The oscilloscope view (available in tracer test mode) displays measured MCSMU module current or voltage data versus time. The pulsed measurement waveforms appear in a separate window for easy verification of the measurement timings. This function is useful for verifying waveform timings and debugging pulsed measurements. It is available when a tracer test has one or more MCSMU channels being used in pulsed mode. The oscilloscope view can display the pulsed waveform timings at any (user specified) sweep step of the sweep output.

Sampling interval: 2 μ s

Sampling points: 2000 Sa

Sampling duration: 22 μ s to 24 ms

Marker function:

- Read-out for each data channel

- Resolution: 2 μ s

Data saving:

- Numeric: Text/CSV/XMLSS

- Image: EMF/BMP/JPG/PNG

Quick test mode

A GUI-based Quick Test mode enables you to perform test sequencing without programming. You can select, copy, rearrange and cut-and-paste any application tests with a few simple mouse clicks. Once you have selected and arranged your tests, simply click on the measurement button to begin running an automated test sequence.

Measurement modes

The Keysight B1500A supports the following measurement modes:

IV measurement

- Spot
- Staircase sweep
- Pulsed spot
- Pulsed sweep
- Staircase sweep with pulsed bias
- Sampling
- Multi-channel sweep
- Multi-channel pulsed sweep
- List sweep
- Linear search¹
- Binary search¹

C measurement

- Spot C
- CV (DC bias) sweep
- Pulsed spot C
- Pulsed sweep CV
- C-t sampling
- C-f sweep
- CV (AC level) sweep
- Quasi-Static CV (QSCV)

1. They are supported by FLEX command only.

Sweep measurement

Number of steps: 1 to 10001 (SMU), 1 to 1001 (CMU)

Sweep mode: Linear or logarithmic (log)

Sweep direction: Single or double sweep

Hold time: 0 to 655.35 s, 10 ms resolution

Delay time: 0 to 65.535 s, 100 μ s resolution

0 to 655.35 s, 100 μ s resolution (CV (AC level) sweep, C-f sweep)
Step delay time: 0 to 1 s, 100 μ s resolution
Step output trigger delay time: 0 to (delay time) s, 100 μ s resolution
Step measurement trigger delay time: 0 to 65.535 s, 100 μ s resolution

Sampling (time domain) measurement

Displays the time sampled voltage/current data (by SMU) versus time.

Sampling channels: Up to 10

Sampling mode: Linear, logarithmic (log)

Sampling points:

For linear sampling:

1 to 100,001/(number of channels)

For log sampling:

1 to 1+ (number of data for 11 decades)

Sampling interval range:

100 μ s +20 μ s x (num. of channels – 1) to 2 ms,

10 μ s resolution

2 ms to 65.535 s, 1 ms resolution

* Sampling interval less than 2ms is only supported in linear mode.

Hold time, bias hold time:

-90 ms to -100 μ s, 100 μ s resolution

0 to 655.35 s, 10 ms resolution

Measurement time resolution: 100 μ s

Other measurement characteristics

Measurement control

Single, repeat, append, and stop

SMU setting capabilities

Limited auto ranging, voltage/current compliance, power compliance, automatic sweep abort functions, self-test, and self-calibration

Standby mode

SMUs in “Standby” remain programmed to their specified output value even as other units are reset for the next measurement.

Bias hold function

This function allows you to keep a source active between measurements. The source module will apply the specified bias between measurements when running classic tests inside an application test, in quick test mode, or during a repeated measurement. The function ceases as soon as these conditions end or when a measurement that does not use this function is started.

Current offset cancel

This function subtracts the offset current from the current measurement raw data, and returns the result as the measurement data. This function is used to compensate the error factor (offset current) caused by the measurement path such as the measurement cables, manipulators, or probe card.

Time stamp

The B1500A supports a time stamp function utilizing an internal quartz clock.
Resolution: 100 μ s

Data display, analysis and arithmetic functions

Data Display

X-Y graph plot

X-axis and up to eight Y-axes, linear and log scale, real time graph plotting.

Scale: Auto scale and zoom

Marker: Marker to min/max, interpolation, direct marker, and marker skip

Cursor: Direct cursor

Line: Two lines, normal mode, grad mode, tangent mode, and regression mode

Overlay graph comparison: Graphical plots can be overlaid.

List display

Measurement data and calculated user function data are listed in conjunction with sweep step number or time domain sampling step number. Up to 20 data sets can be displayed.

Data variable display

Up to 20 user-defined parameters can be displayed on the graphics screen.

Automatic analysis function

On a graphics plot, the markers and lines can be automatically located using the auto analysis setup. Parameters can be automatically determined using automatic analysis, user function, and read out functions.

Analysis functions

Up to 20 user-defined analysis functions can be defined using arithmetic expressions.

Measured data, pre-defined variables, and read out functions can be used in the computation, and the result can be displayed.

Read out functions

The read out functions are built-in functions for reading various values related to the marker, cursor, or line.

Data export

X-Y graph plot can be printed or stored as image data to clipboard or mass storage device. (File type: bmp, gif, png, emf). Graph and list data can be exported to Excel.

Arithmetic functions

User functions

Up to 20 user-defined functions can be defined using arithmetic expressions.

Measured data and pre-defined variables can be used in the computation. The results can be displayed on the LCD.

Arithmetic operators

+, -, *, /, ^, abs (absolute value), at (arc tangent), avg (averaging), cond (conditional evaluation), delta, diff (differential), exp (exponential), integ (integration), lgt (logarithm, base 10), log (logarithm, base e), mavg (moving average), max,min, sqrt, trigonometric function, inverse trigonometric function, and so on.

Physical constants

Keyboard constants are stored in memory as follows:

q: Electron charge, 1.602177E-19 C

k: Boltzman's constant, 1.380658E-23

e (e): Dielectric constant of vacuum, 8.854188E-12

Engineering units

The following unit symbols are also available on the keyboard:

a (10⁻¹⁸), f (10⁻¹⁵), p (10⁻¹²), n (10⁻⁹), u or μ (10⁻⁶), m (10⁻³), k (10³), M (10⁶), G (10⁹), T (10¹²), P (10¹⁵)

Data management

Workspace (Built-in database)

- EasyEXPERT group+ supports the built-in database called “workspace”. Workspaces are created on a SSD, and they enable to manage and access all the measurement related data without handling numerous files. Every workspace supports the following features:
- Access to measurement capabilities and data stored in the workspace.
- Save/Import/Export measurement settings and data (application library, measurement settings, my favorite setup, and measurement data)
- Recall the setup for measurement reproduction and data for analysis

Data auto record/auto export

EasyEXPERT group+ has the ability to automatically store the measurement setup and data within a workspace. It can also export measurement data in real time, in a variety of formats such as Excel (xlsx).

Import/export files

File type:

Keysight EasyEXPERT format, XML-SS format, CSV format

Data Protection

EasyEXPERT group+ has various options to protect important data as follows.

- Password protection (workspace, test definition and my favorite)
- User level access control (engineer mode/operator mode)

Workspace back-up and portability

EasyEXPERT group+ has the ability to import/export a workspace for back-up and portability.

EasyEXPERT group+ supported instruments and prerequisites

Supported instruments and features

		Precision Current - Voltage Analyzer Series					
		Advanced Device Analyzer		Precision IV Analyzer		Economic IV Analyzer	Discontinued
		B1500A	B1505A	E5270B	E5262/63A E5260A	B2900A Series SMU	4155B/C 4156B/C
Classic Test	I/V Sweep	Yes	Yes	Yes	Yes	Yes	Yes ¹
	Multi-ch I/V Sweep	Yes	Yes	Yes	Yes	Yes	-
	I/V List Sweep	Yes	Yes	Yes	Yes	Yes	-
	I/V-t Sampling	Yes	Yes	-	-	Yes	Yes
	C-V Sweep	Yes	Yes	-	-	-	-
	SPGU Control	Yes	-	-	-	-	-
	GUI based switching matrix control	Yes ²	-	Yes ²	Yes ²	Yes ²	Yes ²
	Direct Control	Yes	Yes	-	-	-	-
Application Test		Yes	Yes	Yes	Yes	Yes	Yes
Tracer Test		Yes (DC/Pulse)	Yes (DC/Pulse)	Yes (DC)	Yes (DC)	Yes (DC/Pulse)	-
Quick Test		Yes	Yes	Yes	Yes	Yes	Yes
Oscilloscope view		Yes ³	Yes ³	-	-	-	-
External instrument driver support	LCR meter (4284A/E4980A)	Yes	Yes	Yes	Yes	Yes	Yes
	Pulse Generator (81110A)	Yes	Yes	Yes	Yes	Yes	Yes
	DVM (3458A)	Yes	Yes	Yes	Yes	Yes	Yes
Prober control in Quick Test mode		Yes ^{4, 5}	Yes ^{4, 5}	Yes ^{4, 5}	Yes ^{4, 5}	Yes ^{4, 5}	Yes ^{4, 5}
Firmware requirement		A.04.00 or later ⁶	A.04.00 or later ⁶	B.01.10 or later	B.01.10 or later	1.0 or later	HOSTC: 03.08 or later SMUC: 04.08 or later

1. PGU and VSU/VMU are supported. Differential voltage measurement of VMU is not supported.
2. B2200/01A and E5250A (with E5252A cards) are supported
3. Only available for supported modules.
4. Cascade Microtech Summit 12000/S300 (Nucleus), Cascade Microtech (Suss MicroTec) PA200/PA300, and Vector Semiconductor VX-2000/VX-3000
5. MPI SENTIO, SemiProbe PILOT (Contact to the prober vender if the latest driver is available.)
6. The latest firmware version is strongly recommended to take full advantage of measurement capabilities.

Prerequisites

Prerequisites to use the EasyEXPERT, WGFMU instrument library and other furnished software on an external PC are as follows.

Operating system and service pack	Microsoft Windows Vista Business SP2 or later (32bit)	Microsoft Windows 7 Professional SP1 or later (32bit/64bit)	Microsoft Windows 8.1 Professional or later (32bit/64bit)	Microsoft Windows 10 Pro or later (32bit/64bit)
Processor	Vista certified PC	Windows 7 certified PC	Windows 8.1 certified PC	Windows 10 certified PC
Supported language	English (US)	English (US)	English (US)	English (US)
Memory	2 GB memory	2 GB memory	2 GB memory	2 GB memory
Display	XGA 1024 x 768 (SXGA 1280 x 1024 recommended)	XGA 1024 x 768 (SXGA 1280 x 1024 recommended)	XGA 1024 x 768 (SXGA 1280 x 1024 recommended)	XGA 1024 x 768 (SXGA 1280 x 1024 recommended)
HDD / SSD	Installation: 1 GB free disk space on the C drive	Installation: 1 GB free disk space on the C drive	Installation: 1 GB free disk space on the C drive	Installation: 1 GB free disk space on the C drive
	Test setup / result data storage: Free disk space more than 30 GB is recommended	Test setup / result data storage: Free disk space more than 30GB is recommended	Test setup / result data storage: Free disk space more than 30GB is recommended	Test setup / result data storage: Free disk space more than 30GB is recommended
.NET Framework	Microsoft .NET Framework 3.5 SP1	Microsoft .NET Framework 3.5 SP1	Microsoft .NET Framework 3.5 SP1	Microsoft .NET Framework 3.5 SP1
IO Libraries	Keysight IO Libraries Suite 16.3, 17.1 update 1 or later (for the Online execution mode)	Keysight IO Libraries Suite 16.3, 17.1 update 1 or later (for the Online execution mode)	Keysight IO Libraries Suite 16.3, 17.1 update 1 or later (for the Online execution mode)	Keysight IO Libraries Suite 17.1 update 1 or later (for the Online execution mode)

Recommended GPIB I/F

		Interface	B1500A	4155B/C 4156B/C
Keysight	82350B/C	PCI	✓ ¹	✓
	82351B	PCIe	✓ ¹	✓
	82357A/B	USB	✓ ²	✓
National Instruments	GPIB-USB-HS	USB	✓ ²	✓

1. A PCI or PCIe card is highly recommended because of stability and speed.
2. USB GPIB interfaces might cause serial poll error intermittently due to the intrinsic communication scheme differences. It is reported that using an even GPIB address sometimes significantly decreases the chance of the error. The NI GPIB-USB-HS is recommended for stability, and the Keysight 82357x is recommended for speed.

Order information

Mainframe	
B1500A	Semiconductor device analyzer mainframe. The following accessories are included 16444A-001 Keyboard 16444A-002 USB mouse 16444A-003 Stylus pen 16493J-001/002 Interlock cable 1.5m or 3.0m* 16493L-001/002 GNDU cable 1.5m or 3.0m * 16494A-001/002 Tri-axial cable 1.5m or 3.0m * N1254A-100 GNDU to Kelvin adaptor CD-ROMs Manuals, Others *Select B1500A-015 or B1500A-030 to specify cable length
B1500A-015	1.5m cable (Cable length is set to 1.5m for standard and add-on packages)
B1500A-030	3.0m cable (Cable length is set to 3.0m for standard and add-on packages)
B1500A-050	50 Hz line frequency
B1500A-060	60 Hz line frequency
B1500A-A6J*	ANSI Z540 compliant calibration
B1500A-UK6*	Commercial calibration certificate with test data
B1500A-ABA	English paper document
B1500A-ABJ	Japanese paper document

* The option A6J and UK6 are available ONLY at the initial shipment.

- Option A6J includes the test data and measurement uncertainties from the calibration and the certificate of calibration stating the instrument has been calibrated using a process in compliance with ANSI Z540 and is operating within the published specifications.
- Option UK6 includes the test data from the calibration and the certificate of calibration stating the instrument has been calibrated and is operating within the published specifications.

Standard packages	
B1500A-A00	Empty Package for Custom Solution
B1500A-A01	Standard Package (MPSMU 4ea. & Cables)
B1500A-A02	High Resolution Package (HRSMU 4ea & Cables)
B1500A-A03	High Power Package (HPSMU 2ea, MPSMU 2ea & Cables)
B1500A-A04	Basic Flash Memory Cell Package (MPSMU 2ea, HRSMU 2ea, SPGU, Accessories)
Add-on packages	
B1500A-A10	HPSMU Add-on (HPSMU 1ea. & Cables)
B1500A-A11	MPSMU Add-on (MPSMU 1ea. & Cables)
B1500A-A17	HRSMU Add-on (HRSMU 1ea. & Cables)
B1500A-A1A	MCSMU Add-on (MCSMU 1ea. connection box & cables)
B1500A-A1B	MCSMU Add-on (MCSMU 2ea. connection box & cables)
B1500A-A20	MFCMU Add-on (MFCMU, Cable)
B1500A-A25	HVSPGU Add-on (HVSPGU 1ea. & Cables)
B1500A-A28	ASU (Atto Sense Unit) Add-on for HRSMU (ASU 1ea. & Cables)
B1500A-A29	ASU (Atto-sense and switch unit) Add-on for MPSMU (ASU 1ea. & Cables)
B1500A-A30	WGFMU Add-on (WGFMU 1ea. RSU 2ea. & Cables)
B1500A-A31	WGFMU Add-on with Connector Adapter (WGFMU 1ea, RSU 2ea, Cables & Connector Adapter)
B1500A-A3P	WGFMU probe cable kit (8 probe cables. WGFMU is not included.)
B1500A-A5F	Test fixture for packaged device measurement (16442B 1ea)
Other accessories	
N1301A	CMU Accessories for B1500
N1301A-100	SMU CMU unify unit (SCUU)
N1301A-102	SMU CMU unify unit cable (3m)
N1301A-110	SMU CMU unify unit magnetic stand
N1301A-200	Guard switch unit (GSWU)
N1301A-201	Guard switch unit cable (1 m)
N1301A-202	Guard switch unit cable (3 m)

Package Option Contents ¹

Standard packages

Item	Description	Qty
B1500A-A01 Standard package		
B1511B	MPSMU (Medium Power SMU)	4
16494A-001/002	Triaxial cable 1.5m or 3.0m	8
B1500A-A02 High resolution package		
B1517A	HRSMU (High Resolution SMU)	4
16494A-001/002	Triaxial cable 1.5m or 3.0m	8
B1500A-A03 High power package		
B1511B	MPSMU (Medium Power SMU)	2
B1510A	HPSMU (High Power SMU)	2
16494A-001/002	Triaxial cable 1.5m or 3.0m	8
B1500A-A04 Basic flash memory cell package		
B1511B	MPSMU (Medium Power SMU)	2
B1517A	HRSMU (High Resolution SMU)	2
B1525A	HVSPGU (Pulse Generator Unit)	1
16493P-001 / 002	SPGU CABLE (SMA-TO-COAXIAL) 1.5 m or 3.0 m	2
16440A	SMU/PGU Pulse Selector	1
16440A-003	Control Cable 40cm (2nd Selector)	1
16445A	Selector Connection Unit	1
16445A-001	Control Cable For B1500A To 16440A 1.5 m	1
16494A-001	Tri-axial cable 1.5 m	2
16494A-001/002	Triaxial cable 1.5 m or 3.0 m	8

1. Cable length is set by B1500A-015 or B1500A-030 option

Add-on packages

B1500A-A10 HPSMU Add-on package		
B1510A	HPSMU (High Power SMU)	1
16494A-001/002	Triaxial cable 1.5m or 3.0m	2
B1500A-A11 MPSMU Add-on package		
B1511B	MPSMU (Medium Power SMU)	1
16494A-001/002	Triaxial cable 1.5m or 3.0m	2
B1500A-A17 HRSMU Add-on package		
B1517A	HRSMU (High Resolution SMU)	1
16494A-001/002	Triaxial cable 1.5m or 3.0m	2
B1500A-A1A MCSMU Add-on package		
B1514A	MCSMU (Medium Current SMU)	1
16494A-001/002	Triaxial cable 1.5m or 3.0m	2
N1255A	2 Channel connection box for MCSMU	1
B1500A-A1B MCSMU Add-on package		
B1514A	MCSMU (Medium Current SMU)	2
16494A-001/002	Triaxial cable 1.5m or 3.0m	4
N1255A	2 Channel connection box for MCSMU	1
B1500A-A20 MFCMU Add-on package		
B1520A	MFCMU	1
N1300A-001/002	CMU cable for B1500A 1.5m or 3.0m	1
B1500A-A25 HVSPGU Add-on package		
B1525A	HVSPGU	1
16493P-001/002	SPGU cable (SMA to Coaxial) 1.5m or 3.0m	2
B1500A-A28/A29 ASU Add-on package		
E5288A	ASU (Atto-sense and switch unit)	1
E5288A-001/002	Triaxial and Dsub cable for ASU 1.5m or 3.0m	1

B1500A-A30 WGFMU Add-on package ²		
B1530A	One WGFMU and two RSUs	1
B1530A-005/002	Two WGFMU cables (1.5m or 3.0m) to connect between WGFMU and RSU	1
B1500A-A31 WGFMU Add-on package with connection adapter²		
B1530A	One WGFMU and two RSUs	1
B1530A-001	Two set of WGFMU cables (0.6m + 2.4m)	1
16493R-801	WGFMU connector adapter	2
B1500A-A3P WGFMU Probe cable kit		
16493R-101	SSMC-SSMC cable (50mm) for current return path	2
16493R-102	SSMC-SSMC cable (70mm) for current return path	2
16493R-202	SMA-SSMC cable (200mm) between RSU and DC probe	2
16493R-302	SMA-SMA cable (200mm) between RSU and RF probe	2
B1500A-A5F Test fixture for packaged device measurement		
16442B	Test fixture	1
	Test fixture adapter	1
	Universal socket module	2
	28 pin DIP socket module	1
	Blank PTFE board	1
	Cables used in test fixture adapter	39
	Carrying case	1

2. Order 16493R-802 if magnet stand is necessary for RSU

Keysight Precision Current-Voltage Analyzer Series and Power Device Analyzer Series

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